## Issue Classification

| Application/Control No. | Applicant(s)/Patent Under Reexamination |
|---|---|
| 10689721 | BAN ET AL. |
| **Examiner** | **Art Unit** |
| ALEX LIEW | 2624 |

| ORIGINAL | | INTERNATIONAL CLASSIFICATION | | | | | |
|---|---|---|---|---|---|---|---|
| CLASS | SUBCLASS | CLAIMED | | | | | NON-CLAIMED |
| 382 | 154 | G | 0 | 6 | K | 9 / 00 (2006.01.01) | |

| CROSS REFERENCE(S) | |
|---|---|
| CLASS | SUBCLASS (ONE SUBCLASS PER BLOCK) |
| | |

☒ Claims renumbered in the same order as presented by applicant ☐ CPA ☐ T.D. ☐ R.1.47

| Final | Original | Final | Original | Final | Original | Final | Original | Final | Original | Final | Original | Final | Original | Final | Original |
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| /ALEX LIEW/<br>Examiner.Art Unit 2624 | 3/3/09 | **Total Claims Allowed:** | |
| (Assistant Examiner) | (Date) | 18 | |
| /MATTHEW C BELLA/<br>Supervisory Patent Examiner.Art Unit 2624 | 02/03/2009 | O.G. Print Claim(s) | O.G. Print Figure |
| (Primary Examiner) | (Date) | 2 | 1 |